

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1210	Oct-97	9643 C1	HYUNDAI	DL728002AAC	3.0μ OX/NI	16 SOIC

**STRESS/JOB NO.**

**READPOINT  
(Sample Size/No. of Fails)**

Preconditioning (P/C):	<u>Electrical</u>	<u>Cum %</u>
Bake, 125°C, 24 Hr	238/0	0.0%
Moisture Soak, 85°C/85% RH, 168 Hr		
Vapor Phase Reflow, 3 Passes, P-20676		

Sonoscan	<u>Post Vapor Phase</u>
P-20755	

Infant / High Voltage Life	<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
125°C, 7.0 V.	233/0	77/0	77/0	30 Fits
P-20756, P-20809				

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle	<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
-55°C to +125°C	40/0	40/0	0.0%
P-20810			

Biased Moisture	<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
85°C/85% RH, 5.5 V.	77/0		
P-20811			

Autoclave	<u>96 Hr</u>	<u>Cum %</u>
121°C/100% RH, 2 Atmos	38/0	0.0%
P-20812		

**Failure Mode**

**Failure Analysis**